

Description

The SI7129DN-T1-GE3 uses advanced trench technology to provide excellent R_{DS(ON)}, low gate charge and operation with gate voltages as low as 4.5V. This device is suitable for use as a Battery protection or in other Switching application.

General Features

 $V_{DS} = -30V I_{D} = -50 A$

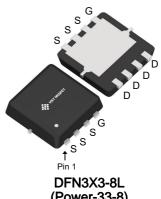
 $R_{DS(ON)}$ < 13m Ω @ V_{GS} =-10V

Application

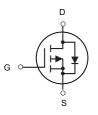
Battery protection

Load switch

Uninterruptible power supply



(Power-33-8)



P-Channel MOSFET

Package Marking and Ordering Information

Product ID	Pack	Brand	Qty(PCS)
SI7129DN-T1-GE3	DFN3X3-8L(Power-33-8)	HXY MOSFET	5000

Absolute Maximum Ratings (Tc=25°C unless otherwise specified)

		Rating		11.24	
Symbol	Parameter	10s	Steady State	Units	
VDS	Drain-Source Voltage	-30		V	
VGS	Gate-Source Voltage	±20		V	
I _D @T _C =25°C	Continuous Drain Current, V _{GS} @ -10V ¹	-50		Α	
I _D @T _C =100°C	Continuous Drain Current, V _{GS} @ -10V ¹	-27		Α	
In@T _A =25°C	Continuous Drain Current, V _{GS} @ -10V ¹	-14.3	-9	Α	
I _D @T _A =70°C	Continuous Drain Current, V _{GS} @ -10V ¹	-11.4	-7.2	Α	
IDM	Pulsed Drain Current ²	-130		Α	
EAS	Single Pulse Avalanche Energy³	125		mJ	
IAS	Avalanche Current	-50		Α	
P _D @T _C =25°C	Total Power Dissipation ⁴	37		W	
P _D @T _A =25°C	P _D @T _A =25°C Total Power Dissipation ⁴		1.67	W	
TSTG	Storage Temperature Range	-55 to 150		°C	
TJ	Operating Junction Temperature Range	-55 to 150		°C	



R₀JA	Thermal Resistance Junction-Ambient ¹	75	°C/W
R _θ JA	Thermal Resistance Junction-Ambient ¹ (t ≤10s)	30	°C/W
ReJC	Thermal Resistance Junction-Case ¹	3.36	°C/W

Electrical Characteristics (T_J=25°C, unless otherwise noted)

Symbol	Parameter	Conditions	Min.	Тур.	Max.	Unit
BVDSS	Drain-Source Breakdown Voltage	V _{GS} =0V , I _D =-250uA	-30			V
△BVDSS/△TJ	BVDSS Temperature Coefficient	Reference to 25°C , I _D =-1mA		-0.0232		V/°C
	Static Drain-Source On-Resistance ²	V _{GS} =-10V , I _D =-30A		9	13	mΩ
Rds(on)		V _{GS} =-4.5V , I _D =-15A		16	22	
V _G S(th)	Gate Threshold Voltage		-1.2		-2.5	V
$\triangle V_{GS(th)}$	V _{GS(th)} Temperature Coefficient	V _{GS} =V _{DS} , I _D =-250uA		4.6		mV/°C
	Drain-Source Leakage Current	V _{DS} =-24V , V _{GS} =0V , T _J =25°C			-1	- uA
Ipss		V _{DS} =-24V , V _{GS} =0V , T _J =55°C			-5	
Igss	Gate-Source Leakage Current	V _{GS} =±20V , V _{DS} =0V			±100	nA
gfs	Forward Transconductance	V _{DS} =-5V , I _D =-30A		30		S
Rg	Gate Resistance	V _{DS} =0V , V _{GS} =0V , f=1MHz		9		Ω
Qg	Total Gate Charge (-4.5V)			22		
Qgs	Gate-Source Charge	V _{DS} =-15V , V _{GS} =-4.5V , I _D =- 15A		8.7		nC
Qgd	Gate-Drain Charge	100		7.2		
T _{d(on)}	Turn-On Delay Time			8		
Tr	Rise Time	V _{DD} =-15V , V _{GS} =-10V ,		73.7		
T _{d(off)}	Turn-Off Delay Time	—R _G =3.3 —I _D =-15A		61.8		ns
T _f	Fall Time			24.4		
Ciss	Input Capacitance			2215		
Coss	Output Capacitance	V _{DS} =-15V , V _{GS} =0V , f=1MHz		310		pF
Crss	Reverse Transfer Capacitance			237		
Is	Continuous Source Current ^{1,5}				-42	Α
Іѕм	Pulsed Source Current ^{2,5}	V _G =V _D =0V , Force Current			-130	Α
Vsp	Diode Forward Voltage ²	V _{GS} =0V , I _S =-1A , T _J =25°C			-1	V
trr	Reverse Recovery Time	IF=-15A , dI/dt=100A/μs ,		19		nS
Q _{rr}	Reverse Recovery Charge	T _J =25°C		9		nC

Note:

- 1.The data tested by surface mounted on a 1 inch² FR-4 board with 2OZ copper.
- 2.The data tested by pulsed , pulse width $\leq 300 \text{us} \;\; \text{duty cycle} \leq \!\! 2\%$
- 3.The EAS data shows Max. rating . The test condition is V_{DD} =-25V V_{GS} =-10V,L=0.1mH,IAS=-50A,
- 4.The power dissipation is limited by 150°C junction temperature
- 5.The data is theoretically the same as ID and IDM , in real applications , should be limited by total power dissipation.



Typical Characteristics

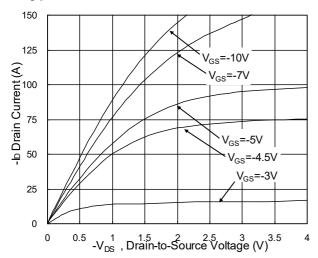


Fig.1 Typical Output Characteristics

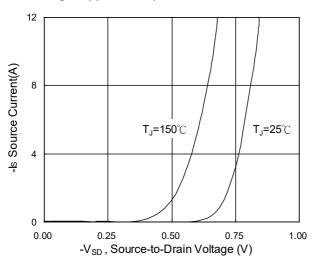


Fig.3 Forward Characteristics of Reverse

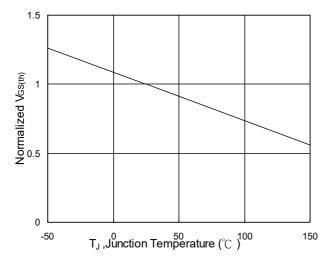


Fig.5 Normalized V_{GS(th)} vs. T_J

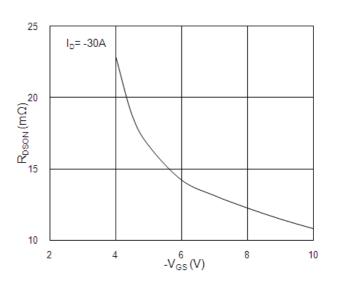


Fig.2 On-Resistance vs. G-S Voltage

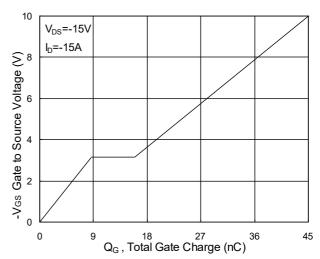


Fig.4 Gate-Charge Characteristics

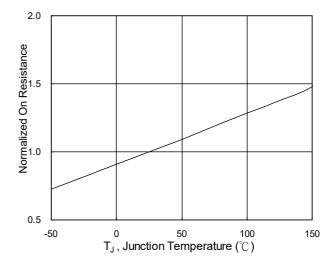
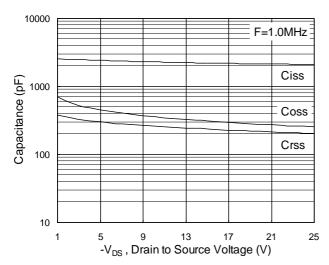


Fig.6 Normalized R_{DSON} vs. T_J



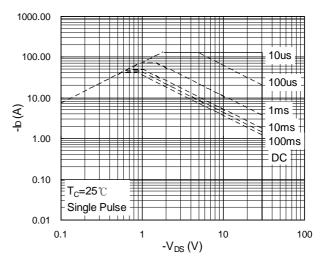


Fig.7 Capacitance

Fig.8 Safe Operating Area

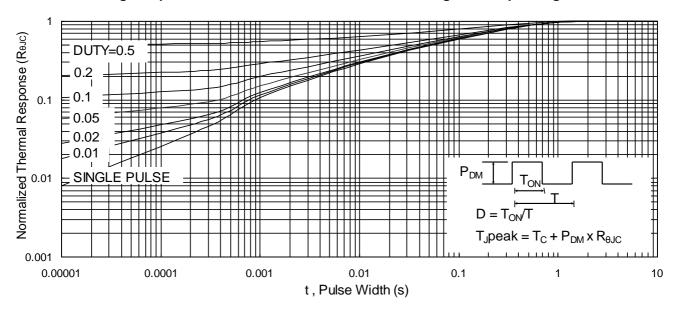


Fig.9 Normalized Maximum Transient Thermal Impedance

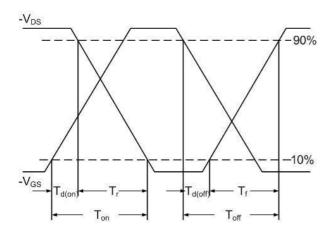


Fig.10 Switching Time Waveform

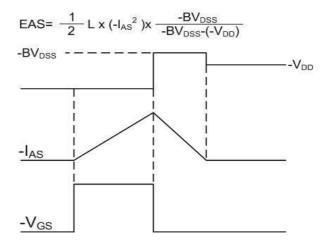
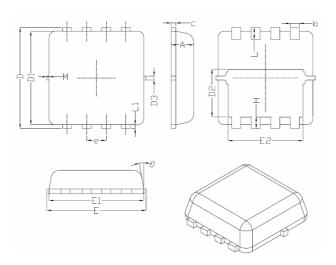


Fig.11 Unclamped Inductive Switching Waveform



DFN3X3-8L(Power-33-8) Package Information



Sumb at	Dimensions In Millimeters			
Symbol	Min.	Nom.	Max.	
A	0.70	0.75	0.80	
b	0.25	0.30	0.35	
С	0.10	0.15	0.25	
D	3.25	3.35	3.45	
D1	3.00	3.10	3.20	
D2	1.48	1.58	1.68	
D3	-	0.13	-	
E	3.20	3.30	3.40	
E1	3.00	3.15	3.20	
E2	2.39	2.49	2.59	
е	0.65BSC			
Н	0.30	0.39	0.50	
L	0.30	0.40	0.50	
L1	-	0.13	-	
M	*	*	0.15	
θ		10 [°]	12 [°]	



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